
Samsung WinCE User Manual

General Description and Name

Samsung WinCE. Creates a table of the device and places it in the last block of the device. Bad blocks are remapped to the last available good block, e.g. if a device has 4096 blocks, the table will be put in block 4095, the first bad block found will be put in 4094, then the next 4093. The first block is required to be good, and the total number of bad blocks will be recorded in the position of the table that would have been used to map the location of block 0.

Relevant User Options

The following special features on the special features tab apply to this scheme. The default values might work in some cases but please make sure to set the right value according to your system.

Please note only the below special feature items are related to this scheme and ignore any others. If any of below items doesn't exist, please check whether the right version has been installed or contact Data I/O for support by submitting Device Support Request through this address:

<http://www.dataio.com/support/dsr.asp>

Bad Block Handling Type = "Samsung WinCE"

Spare area : Please refer to "Description of common NAND special features.pdf". *Normally set as "Enabled" or "Disabled" for this BBM.*[Default 'Disabled']

Required good block area: Start block = "0" Please refer to "Description of common NAND special features.pdf".

Required good block area: Number of blocks = "0" Please refer to "Description of common NAND special features.pdf".

Special Notes

The spare area in this scheme can either be programmed with the customer's image file, or it can be ignored. ECC is not an option with this particular scheme. The bad block marks are always located in the spare area. (Byte 517 for x8 devices)

There is a related document "Sam WinCE Mem Map.xls" from Samsung.

The first page of the image will be written as the first page of the table of contents in the last block of the device. The second page of the image will be written starting at the

beginning of block 0. Special care should be taken into account if the spare area option is set to “enabled”. In that case, byte 517 of each page (the sixth byte of the spare area in each page) needs to be left at 0xFF. This is because byte 517 is used to identify bad blocks in the device. If you program one of these bytes to something other than 0xFF, there will be no way for anyone to distinguish a factory marked bad block from a block that has had byte 517 programmed by the programmer.

If the spare area is not to be programmed, then the image should not contain any data for the spare area.

Revision History

V1.0 June 11, 2009
Create this spec.

Appendix

You can get the file “Description of common NAND special features.pdf” from <http://ftp.dataio.com/FCNotes/BBM/>